

# Search Notes



Application/Control No.

10/797,147

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

MOSCALUK ET AL.

Art Unit

2816

## SEARCHED

Class	Subclass	Date	Examiner
327	198	03.11.05	Mh
	199	T	T
	205	T	T
	208	T	T
	222	T	T
	228	T	T
327	203	07.19.05	Mh
365	145	T	T
327	175	T	T
327	215	T	T

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	03.11.05	Mh
EAST See attachment	07.19.05	Mh